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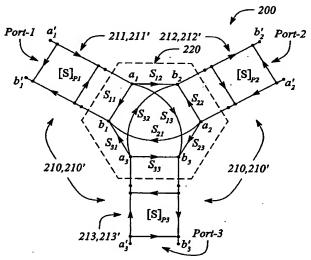
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(54) Title: CORRECTING TEST SYSTEM CALIBRATION AND TRANSFORMING DEVICE MEASUREMENTS WHEN USING MULTIPLE TEST FIXTURES



(57) Abstract: A test system and methods using the test system correlate measurements of a device under test (DUT) regardless of which test fixture is used for in-fixture testing of the DUT. The test system includes test equipment, a test fixture that interfaces the DUT to the test equipment, a computer and a computer program executed by the computer. The computer program includes instructions that implement determining a port-specific difference array for test fixtures used with the test system. The difference array describes a difference between the test fixtures at a corresponding test port thereof. The method includes determining the difference array, measuring a performance of the DUT in a second test fixture, and applying the difference array such that the measured performance approximates a hypothetical DUT performance for the DUT as if mounted in a first test fixture.

